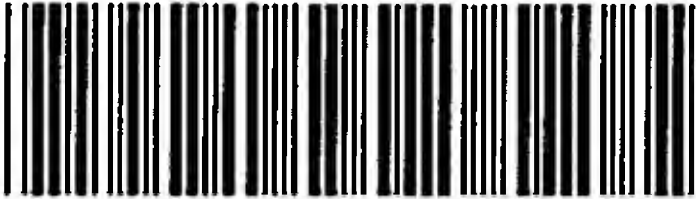


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/604,343	CHANG ET AL.	
	Examiner	Art Unit	
	Thien M. Le	2876	

SEARCHED			
Class	Subclass	Date	Examiner
235	472.01		
	462.01		
	462.33		
	462.43		
	454		
	494		
	483		
	479		
	475	12/12/2005	LTM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR